

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8842	430/5.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:10
L2	423	216/12.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:11
L3	479038	mask or photomask or reticle or \$3PSM	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:11
L4	289088	repair\$3 or (defect or damage or pit or divot) near2 correct\$3	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:13
L5	2988253	etch\$3 or cut\$4 or scratch\$3 or groov\$3 or trench\$3	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:14
L6	4384470	substrate or base	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:14
L7	17162	atomic force or AFM	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:15
L8	2992	250/306-307.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:15
L9	509	382/144.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:15
L10	637729	topograph\$6 or topolog\$4 or three dimension\$4 or "3" dimension\$4 or "3" D or "3D"	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:17
L11	34531	(diffraction or artificial) grating	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:17
L12	5651	effective refractive index	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:17
L13	2838	subwavelength or sub wavelength or subresolution or sub resolution	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:18
L14	4959657	wid\$2 or narrow\$3 or siz\$2 or dimension\$2	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:19
L15	913	703/6.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:19

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L16	514	702/35-36.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:19
L17	1145	700/98,110,118.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:20
L18	3088	optic\$4 near2 simulat\$3	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:20
L19	393	(1 or 2 or 9) and (3 same 4).ti,ab.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:28
L20	161	19 and (3 same 4 same 5 same 6)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:23
L21	1	20 and (5 same 13 same 14)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:29
L22	972	(1 or 2 or 9) and (3 same 4)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:28
L23	1	22 and (3 same 5 same 6 same 13 same 14) not 21	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:31
L24	9	22 and (3 same 5 same 13 same 14) not 21 not 23	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:32
L25	14	22 and (3 same 5 same 13) not 21 not 23 not 24	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:32
L26	3	22 and (11 same 13) not 21 not 23 not 24 not 25	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:34
L27	1	22 and 12 not 21 not 23 not 24 not 25 not 26	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:35
L28	25	(3 same 5 same 6 same 12) not 21 not 23 not 24 not 25 not 26 not 27	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:38
L29	9	(5 same 6 same 11 same 13) not 21 not 23 not 24 not 25 not 26 not 27 not 28	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:41
L30	5	(1 or 2 or 8 or 9) and (3 same 4 same 5 same 6 same 7) not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:45

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L31	1	(3 same 4 same 5 same 6 same 7) not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:47
L32	1521906	quartz or silica or glass	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:46
L33	217	(32 same 5 same 6 same 7) not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:51
L34	71	3 and 33	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:50
L35	10	34 and (11 or 12 or 13)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:50
L36	1	(8 or 9 or 15 or 16 or 17) and ((3 or 32) same (4 or 5) same 10 same 18) not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:56
L37	484	(8 or 9 or 15 or 16 or 17) and ((4 or 5) same (10 or 18)) not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:00
L38	231	37 and (3 or 32)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:58
L39	2	38 and (10 same 18)	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:58
L40	2113	716/19-21.ccls.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:59
L41	14	38 and 40 not 39	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 15:59
L42	153	20 not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:02
L43	230	19 not 20 not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:03
L44	419	3 same 4 same 5 same 6 not 19 not 20 not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:05

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L45	53	34 not 19 not 20 not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41 not 44	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:07
L46	210	38 not 19 not 20 not 21 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41 not 44 not 45	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:08
L47	215	(Ming near2 Lu or King Chang near2 Shu or Bin Chang near2 Chang or Ki Wei near2 Kung).in. not 19 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41 not 44 not 45 not 46	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:10
L48	6198	(Taiwan Semiconductor Manufacturing).as. not 19 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41 not 44 not 45 not 46	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:12
L49	9	47 and 48	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:11
L50	206	47 not 49	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:11
L51	266	1 and (3 same 4) and (5 same 6) not 19 not 23 not 24 not 25 not 26 not 27 not 28 not 29 not 30 not 31 not 35 not 36 not 39 not 41 not 44 not 45 not 46 not 49 not 50	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:13
L52	4	((mask or photomask or reticle or \$3PSM) and (repair\$3 or (defect or damage or pit or divot) near2 correct\$3) and (etch\$3 or cut\$4 or scratch\$3 or groov\$3 or trench\$3 or grating) and (wavelength or wave length) and (refractive index)).clm.	US-PGPUB; USPAT; EPO; JPO	ADJ	ON	2007/06/04 16:18